Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/699,548	HOEY ET AL.
Examiner	Art Unit
Michael Peffley	3739

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Class	Subclass	Date	Examiner
606	1/32- 34,41, 45- 50	5/27/2005	MP
607	101,102	5/27/2005	MP
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